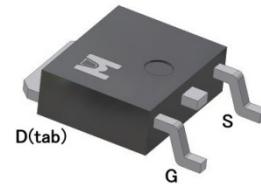


N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV _{DSS}	200V
R _{DSON} (MAX.)	120mΩ
I _D	18A



UIS, 100% Tested

Pb-Free Lead Plating & Halogen Free



ABSOLUTE MAXIMUM RATINGS (T_C = 25 °C Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V _{GS}	±30	V
Continuous Drain Current	T _C = 25 °C	I _D	18	A
	T _C = 100 °C		12	
Pulsed Drain Current ¹		I _{DM}	60	
Avalanche Current		I _{AS}	11	
Avalanche Energy	L = 1mH, ID=11A, RG=25Ω	E _{AS}	60.5	mJ
Repetitive Avalanche Energy ²	L = 0.5mH	E _{AR}	30.2	
Power Dissipation	T _C = 25 °C	P _D	69	W
	T _C = 100 °C		27	
Operating Junction & Storage Temperature Range		T _j , T _{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R _{θJC}	1.8	62.5	°C / W
Junction-to-Ambient	R _{θJA}			

¹Pulse width limited by maximum junction temperature.

²Duty cycle ≤ 1%

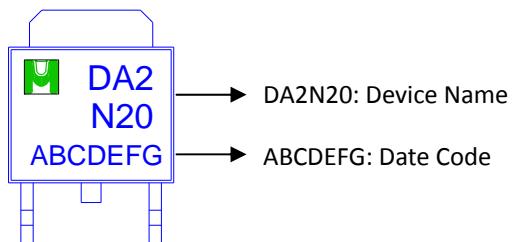
ELECTRICAL CHARACTERISTICS ($T_c = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	200			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	2.0	3.2	4.5	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 30\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 160\text{V}, V_{\text{GS}} = 0\text{V}$			1	μA
		$V_{\text{DS}} = 130\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$			25	
On-State Drain Current ¹	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = 5\text{V}, V_{\text{GS}} = 10\text{V}$	18			A
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 10\text{V}, I_D = 10.5\text{A}$		105	120	$\text{m}\Omega$
		$V_{\text{GS}} = 7\text{V}, I_D = 10.5\text{A}$		115	140	
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = 5\text{V}, I_D = 10.5\text{A}$		12		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 25\text{V}, f = 1\text{MHz}$		2860		pF
Output Capacitance	C_{oss}			143		
Reverse Transfer Capacitance	C_{rss}			46		
Total Gate Charge ^{1,2}	Q_g	$V_{\text{DS}} = 100\text{V}, V_{\text{GS}} = 10\text{V}, I_D = 10.5\text{A}$		36.4		nC
Gate-Source Charge ^{1,2}	Q_{gs}			10.4		
Gate-Drain Charge ^{1,2}	Q_{gd}			13.4		
Turn-On Delay Time ^{1,2}	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = 100\text{V}, I_D = 1\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GS}} = 6\Omega$		25		nS
Rise Time ^{1,2}	t_r			180		
Turn-Off Delay Time ^{1,2}	$t_{\text{d}(\text{off})}$			250		
Fall Time ^{1,2}	t_f			200		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_c = 25^\circ\text{C}$)						
Continuous Current	I_s				18	A
Pulsed Current ³	I_{SM}				60	
Forward Voltage ¹	V_{SD}	$I_F = I_s, V_{\text{GS}} = 0\text{V}$			1.5	V

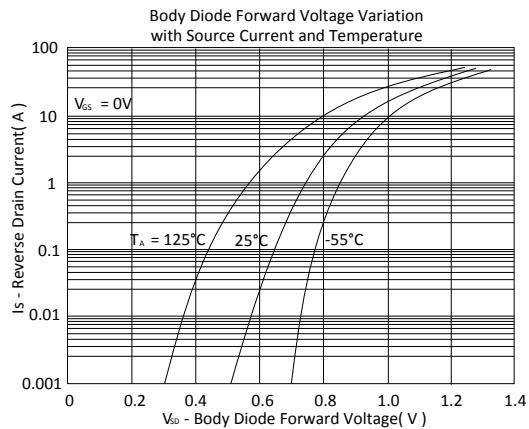
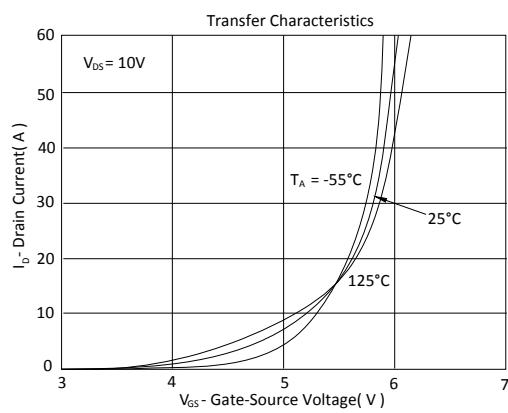
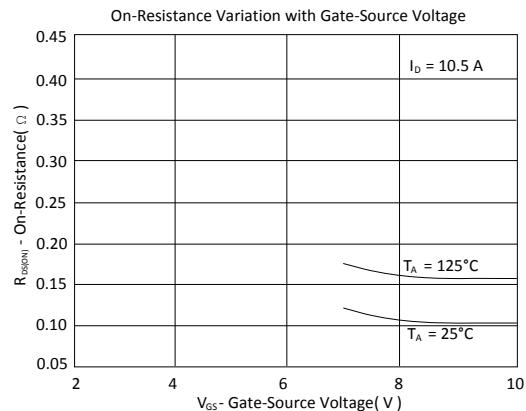
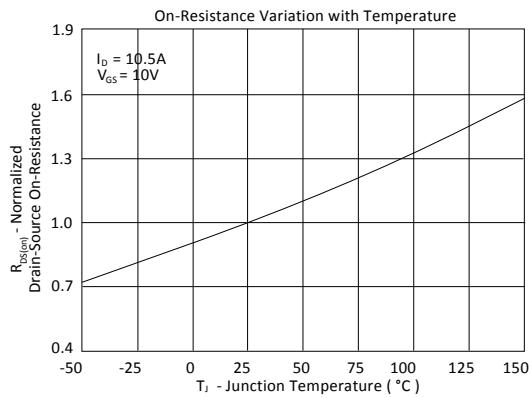
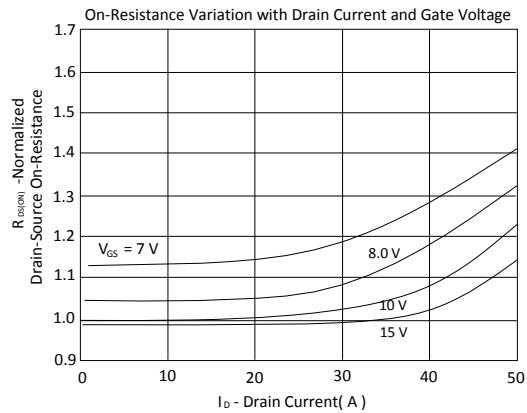
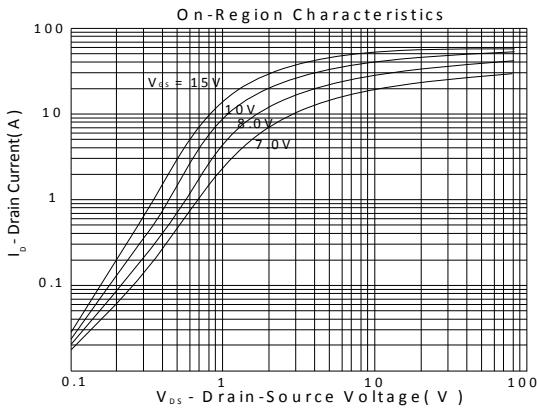
¹Pulse test : Pulse Width $\leq 300 \mu\text{sec}$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.

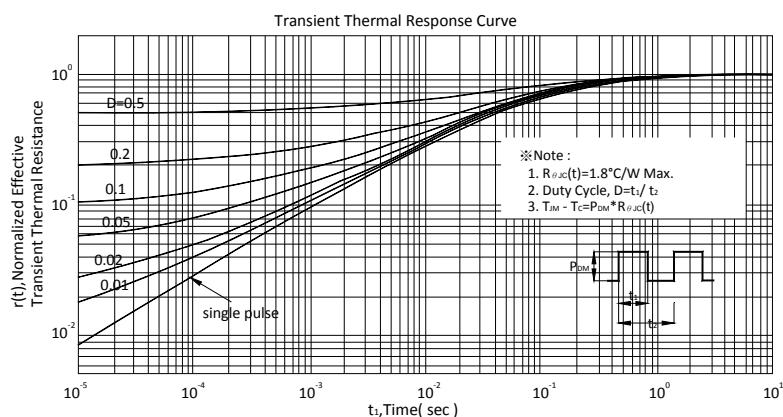
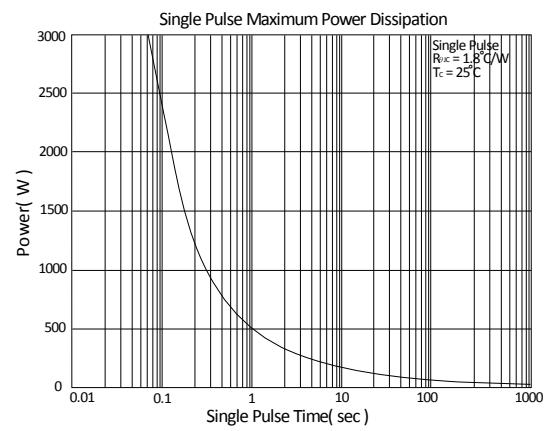
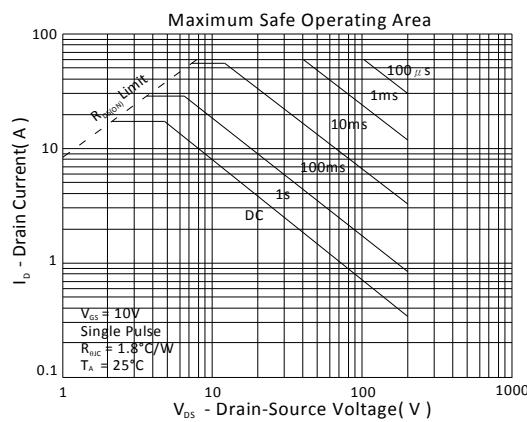
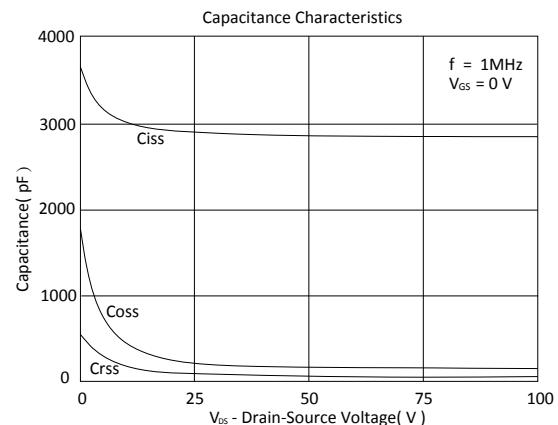
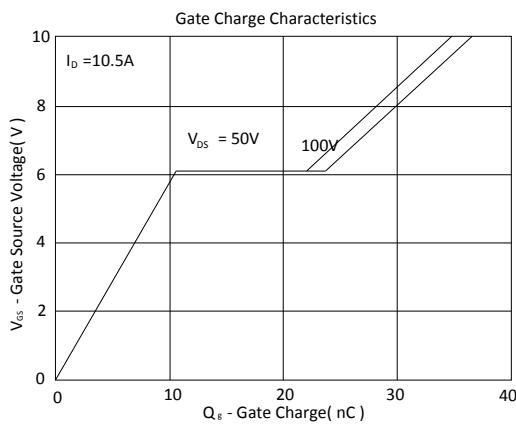
Ordering & Marking Information:

Device Name: EMDA2N20A for DPAK (TO-252)

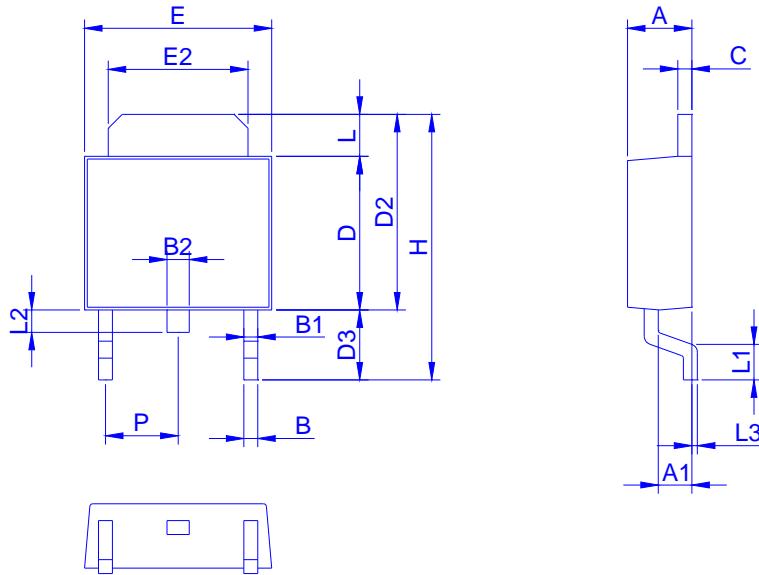


TYPICAL CHARACTERISTICS





Outline Drawing



Dimension in mm

Dimension	A	A1	B	B1	B2	C	D	D2	D3	E	E2	H	L	L1	L2	L3	P
Min.	2.10	0.95	0.30	0.40	0.60	0.40	5.30	6.70	2.20	6.40	4.80	9.20	0.89	0.90	0.50	0.00	2.10
Max.	2.50	1.30	0.85	0.94	1.00	0.60	6.20	7.30	3.00	6.70	5.45	10.15	1.70	1.65	1.10	0.30	2.50

Footprint

